PCN	PCN Number: 20191127000.1 PCN Date: Jan 13, 2020								
Title: Qualification of additional Fab site (UMC-F12X) and Assembly site (SCK) options for select devices						, , , , , , , , , , , , , , , , , , ,			
Customer Contact:			PCN Manager			De	pt: Quality Services		
Proposed 1 st Ship Date:					Estimated Sample Availability:			Date provided at sample request.	
Cha	nge Type:								
M	Assembly	Site	Assembly Pro					Assembly Materials	
	Design		Electrical Spe				•	chanical Specification	
H	Test Site Wafer Bun	on Sito	Packing/Shipp					t Process fer Bump Process	
	Wafer Fab			Wafer Bump Material Wafer Fab Materials				fer Fab Process	
	Walci Tab	Site		Part number change			J Wai	ici i ub i i occis	
				PCN D					
Des	cription o	f Change:							
	Texas Instruments is please and Assembly site (SCK) op		tions for the selected of					duct Affected" section.	
	Fab Site	Process	Wafe	er Diameter	Fab Site	Proc	cess	Wafer Diameter	
	UMC-F12	C28		300 mm	UMC-F12X	C	28	300 mm	
The	There are no Assembly material differences between sites.								
Rea	son for Ch	nange:							
	tinuity of S								
	Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):								
Non	e								
Ant	icipated in	npact on Ma	terial	Declaration					
No Impact to the Material Declarations or Product Content reproduction data and will be available follow release. Upon production release the revision obtained from the TI ECO website.			ving the production						
Cha	Changes to product identification resulting from this PCN:								
Fal	Site Inform	nation:							
			nip Site Origin (20L)		nip Site Country Code (21L)		е	Chip Site City	
	UMC-F12		F12		TWN			Tainan	
	UMC-F12X UCX		(CHN			Xiamen		
Assembly Site Information:									
	Assembly Site		Origin (22L)		sembly Country Code (21L)		٠	Assembly Site City	
	Amkor K4		AMP		KOR KOR			Gwangju	
	STATS ChipPAC		SCK		KOR			Incheon	

Sample product shipping label (not actual product label)



MSL '2 /260C/1 YEAR SEAL DT /235C/UNLIM 03/29/04 1

OPT: ITEM: (L)T0:1750



(1P) SN74LS07NSR (D) 0336 3959047MLA 4W) TKY(1T) 7523483SI2 P) (2P) REV: (21L) CCO:USA (20 SHE (22L) ASO: MLA (23L) ACC. MYS

Product Affected:

1 Todade / Infoceda						
AM5716AABCD	AM5716AABCX	AM5716AABCXEA	AM5718AABCXA			
AM5716AABCDA	AM5716AABCXA	AM5718AABCX	AM5718AABCXEA			
AM5716AABCDEA						

Qualification Report

Approved on 17-Dec-2019

Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: 791842BABCQ	QBS Process Reference: X5777BXGABC	QBS Process Reference: X5777BXGABC	QBS Package Reference: <u>X5777BXGABC</u>
HTSL	High Temp Storage Life, 150C	1000 Hours	-	2/154/0	1/77/0	3/231/0
HTOL	High Temp. Operating Life, 125C	1000 Hours	1/77/0	2/154/0	1/77/0	-
LU	Latch-up, 125C	+/-100 mA	1/6/0	-	-	-
CDM	ESD - CDM	250 V	1/3/0	-	-	-
HBM	ESD - HBM	1000 V	1/3/0	1/3/0	-	-
TC	Temperature Cycle, -55/125C	1000 Cycles	-	2/154/0	1/77/0	3/231/0
THB	Biased Temperature and Humidity, 85C/85%RH	1000 Hours	-	2/154/0	1/77/0	3/231/0
UHAST	Unbiased HAST, 110C/85%RH	264 Hours	-	2/154/0	1/77/0	3/231/0

QBS: Qual By Similarity

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⁻ Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

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